

www.metroind40iot.org

FLORENCE, ITALY / MAY 29-31, 2024

ORGANIZERS

GENERAL CHAIRS

MARCANTONIO CATELANI University of Florence, Italy

LORENZO CIANI

University of Florence, Italy

PASQUALE DAPONTE University of Sannio, Italy

TECHNICAL PROGRAM CHAIRS

OSCAR CASAS

Universitat Politècnica de Catalunya, Spain

EMILIANO SCHENA

Università Campus Bio-Medico di Roma, Italy

MAURO SERPELLONI

University of Brescia, Italy

IMPORTANT DATES

DECEMBER 15, 2023

SPECIAL SESSION PROPOSAL SUBMISSION DEADLINE

March 15, 2024

EXTENDED ABSTRACT SUBMISSION DEADLINE

APRIL 7, 2024

EXTENDED ABSTRACT NOTIFICATION

APRIL 21, 2024

FINAL PAPER SUBMISSION DEADLINE

The Fourth Industrial Revolution represents a fundamental change in the way we live, work, and relate to one another. It is a new chapter in human development, enabled by technology advances that are commensurate with those of the first, second, and third industrial revolutions. The speed, breadth, and depth of this revolution are forcing us to rethink how countries should develop and how organizations create value.

The **7**th **edition** of **IEEE MetroInd4.0&IoT** aims to discuss the contributions both of the metrology for the development of Industry 4.0 and IoT and the new opportunities offered by Industry 4.0 and IoT for the development of new measurement methods and instruments.

Topics for IEEE MetroInd4.0&IoT 2024 include:

- · Industrial sensors;
- Virtual sensors, sensor interfacing;
- · Wireless sensor networks and IoT;
- · Sensors Data Management;
- · Measurement applications based on IoT;
- IoT enabled sensors and measurement systems;
- Industrial IoT and Factory of Things and Internet of Things;
- · Wearables and Body Sensor Networks;
- · Localization Technologies.







In addition to regular papers, many initiatives and opportunities such as special sessions, exhibits, tutorials, demos, student contests, journal papers, and others are planned to enhance your experience with the conference, and will make IEEE MetroInd4.0&IoT 2024 a vibrant event to meet with people in instrumentation and measurement for Industry4.0 and IoT applications. Papers that are accepted and presented will be submitted for inclusion in the IEEE Xplore Digital Library.

